Message from the General Chair and Program Chair

Yashwant K. Malaiya  
General Chair

Sankaran M. Menon  
Program Chair

It is our pleasure to welcome you to the Fourth IEEE International Workshop on IDDQ Testing. This workshop is being held for the first time in conjunction with the International Conference on Computer Aided Design (ICCAD), in San Jose, CA. Sub-micron VLSI devices present new testing challenges — especially when IDDQ testing is used. To address this issue, the theme that we have selected is “IDDQ Testing of Sub-Micron VLSI.” This year’s workshop also includes a tutorial on IDDQ testing and a panel session on the “Role of IDDQ Testing in Deep Sub-Micron Test Suite.” The workshop provides a unique forum for researchers and practitioners to address questions and potential solutions, as well as exchange valuable information on related experiences.

The sessions have been structured to provide time for attendee participation within each session. So, feel free to ask questions and please share your IDDQ and testing related experiences with the audience.

This workshop is the result of considerable time and effort from many dedicated individuals in the field. We wish to thank the authors for submitting their work and the many reviewers for their timely reviews. We are grateful to the Program Committee and the Steering Committee for ensuring a quality program. We would also like to thank Anura Jayasumana for helping with the organization of the workshop and we wish to acknowledge the continuing support of the IEEE Computer Society Test Technology Technical Committee.

We hope you will find the workshop to be thought-provoking and informative.

Welcome to IDDQ’98!